

Application/Control No.	Applicant(s)/Patent under Reexamination
10/624,517	CHIANG ET AL.
Examiner	Art Unit

Nhan T. Tran

2622

SEARCHED						
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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PGPUB text search - see search history printout		12/10/2006	NT	

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB) text search all listed databases - see search history printout	12/6/2006	NT		
348/294-324 (text search - see search history printout)	12/6/2006	NT		
348/241-244, 248, 222.1 (text search - see search history printout)	12/6/2006	NT		
257/292 250/208.1 (text search - see search history printout)	12/6/2006	NT		
Discussed at QEM of AU 2622	12/6/2006	NT		
327/53,206,478,543,417 (text search - see search history printout)	12/10/2006	NT		
257/205,272,273,291,292 (text search - see search history printout)	12/10/2006	NT		
Inventorship search - see search history printout	12/10/2006	NT		